

Product Change Notification / NTDO-29TVUD658

Date:

12-May-2021

Product Category:

Ethernet Bridges, Ethernet Controllers, USB Hubs

PCN Type:

Manufacturing Change

Notification Subject:

CCB 4623 Final Notice: Qualification of STA as an additional assembly site for LAN9220, LAN9221, LAN9500 and USB2524 SMSC device families available in 56L VQFN (8x8x0.9mm) package

Affected CPNs:

NTDO-29TVUD658_Affected_CPN_05122021.pdf NTDO-29TVUD658_Affected_CPN_05122021.csv

Notification Text:

PCN Status: Final notification

PCN Type:Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:Qualification of STA as an additional assembly site for LAN9220, LAN9221, LAN9500 and USB2524 SMSC device families available in 56L VQFN (8x8x0.9mm) package.

Pre and Post Change Summary:

	Pre C	Change Post Change			hange	
Assembly Site	ASE Inc. (ASE)		ASE (A	Inc. SE)	STATS Chippac Ltd. (STA)	
Wire material	PdCu Au		PdCu	Au	CuPdAu	

Die attach material	EN-4900F	EN-4900F	8290		
Molding compound material	G631B	G631B	G700E		
Lead frame material	C194	C194	C194		
Lood from a nodella siza	240X240 mils	240X240 mils	236X236 mils		
Lead frame paddle size	See attached pre and post change comparison				
DAP Surface Prep Double Ring		Double Ring	Ring Plating		

Impacts to Data Sheet: None

Change Impact:None

Reason for Change: To improve manufacturability by qualifying STA as an additional assembly site

Change Implementation Status: In Progress

Estimated First Ship Date: July 8, 2021 (date code: 2128)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

	May 2021					July 2021					
Workweek	1 9	2 0	2 1	2 2	2 3	>	2 7	2 8	2 9	3 0	3 1
Final PCN Issue Date		х									
Qual Report Availability		Х									
Estimated First Ship Date								х			

Method to Identify Change: Traceability code

Qualification Report:Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:

May 12, 2021: Issued final notification. Attached the qualification report. Provided estimated first ship date to be on July 08, 2021.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

PCN NTDO-29TVUD658_Pre and Post Change Comparison.pdf PCN_NTDO-29TVUD658_Qual_Report.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our PCN home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the PCN FAQ section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections. NTDO-29TVUD658 - CCB 4623 Final Notice: Qualification of STA as an additional assembly site for LAN9220, LAN9221, LAN9500 and USB2524 SMSC device families available in 56L VQFN (8x8x0.9mm) package

Affected Catalog Part Numbers (CPN)

LAN9220-ABZJ LAN9221-ABZJ USB2524-ABZJ LAN9500-ABZJ-A00 LAN9500I-ABZJ LAN9500-ABZJ LAN9500I-ABZJ-TR

CCB 4623 Pre and Post Change Summary PCN #NTDO-29TVUD658

A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



Lead frame Comparison







QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

PCN #: NTDO-29TVUD658

Date: December 27, 2011

Qualification of STA as an additional assembly site for selected products available in 64L VQFN (9x9x0.85 mm) package. The qualification of STA as additional assembly site for selected LAN922X, LAN9500 and USB2524 devices family available in 56L VQFN (8x8x0.9mm) package will qualify by similarity (QBS). **Purpose:** Qualification of STA as an additional assembly site for selected products available in 64L VQFN (9x9x0.85 mm) package. The qualification of STA as additional assembly site for selected LAN922X, LAN9500 and USB2524 devices family available in 56L VQFN (8x8x0.9mm) package will qualify by similarity (QBS).

.1	Assembly site	STA			
Aisc	CCB No.	4623			
Ā	Qual ID	QAR2010-076			
Material d		C194			
ead	Lead Plating	Ag (Ring plating) / Etched			
	Leadframe Size	4.9 x 4.9 mm			
<u>Bond</u> Wire	Material	PdCu			
<u>Die</u> Att	Part Number	8290			
MC	Part Number	G700E			
	РКС Туре	VQFN			
X	Pin/Ball Count	64			
	PKG width/size	9x9x0.85			

Assembly Process Data

Process	Tost Itom	Critoria	Sampla Siza	Failure/	Remarks
FIDCESS	Test item	Chiena	Sample Size	Tested Qty.	Pass/Fail
Wafer Saw	Topside Chipping	50% max of damage	45 units/lot	0/45	Pass
	Backside Chipping	the guard ring	45 units/lot	0/45	Pass
		125µm max			
Die attach	Epoxy Void	10% max of die area	10 units/lot	0/10	Pass
	Bond Line	10-40µm	10 units/lot	0/10	Pass
Wirebond	Wirepull	3 gr. Min	20 wires/units	0/80	Pass
		C C	4 units		
	Stitchpull	2.5 gr. Min	10 wires/units	0/50	Pass
		_	5 units		
	Ball Shear	8 gr min.	08 ball/units	0/40	Pass
		_	5 units		
	Loop Height	250 µm Max.	10 wires/units	0/20	Pass
			2 units		
	Cratering	0 defects	03 unit/lot	0/3	Pass
	-		All pads		
	Au Intermetallic	60% min. Coverage	1 unit/lot	0/5	Pass
		C C	5 units		
Mold	Wiresweep	10% max of longest	10 units/lot	0/10	Pass
		wire			
Singulation	Package Dim	9+/-0.05mm	10 readings	0/10	Pass
-		9+/-0.05mm	10 readings	0/10	Pass
Plating	Thickness	10-18µm	20 readings	0/20	Pass
Thickness			Ŭ		

SUMMARY RESULT OF RELIABILITY TEST

ITEM	CONDITION	BEF				
	CONDITION	O/S TEST SAT		O/S TEST	SAT	
PRECONDITIONING	30ºC / 60% RH 192 HRS, Level 3 per Jedec	0/240	0/240	0/240	0/240	
TEST ITEM	TEST	TEST		VISUAL	O/S	
(With Pre-Condition)	CONDITION	INTERVAL		Inspection	TEST	
TEMPRATURE CYCLE TEST	JEDEC 22-A104 -65'C~150'C	1000/1500 CYC		500 CYC 0/60		
HIGH TEMPERATURE STORGE TEST	JEDEC 22-A103 150'C	1000/1500 HRS		0/60	0/60	
HAST TEST (NO BIAS)	JEDEC 22-A118 130'C/85%RH 33.5PSIG	100/150 HRS		0/60	0/60	
TEMPERATURE HUMIDITY TEST (NO BIAS)	JEDEC 22-A101 85'C/85%RH	1000/1500 HRS		0/60	0/60	

Test	Sample Size	Spec	Pass/Fail
Physical dimensions	15	Plastic Pkg outlines - internal specs.	15/0
Solderability	15	PI-23 Matte-Sn Plating	15/0
Marking Inspection	1	AP-51	PASS
Packing Inspection	One Inner Box	AP-71	PASS